

**Search Notes**

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Examiner

Lois Zheng

Applicant(s)/Patent under  
Reexamination

NAKAZAWA ET AL.

Art Unit

1742

**SEARCHED**

Class	Subclass	Date	Examiner
205	633-636	4/11/2007	LLZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
inventorship search	4/11/2007	LLZ
Updated EAST search	4/11/2007	LLZ